Automotive SuperQ® 200V N-Channel Power MOSFET

25mΩ, 40A, TO-220

FEATURES

- Industry leading $R_{DS(on)}$ in TO-220 package
- High short-circuit withstand capability (SCWC)
- 100% UIS tested in production
- Low switching losses, Q_{SW} and E_{OSS}

APPLICATIONS

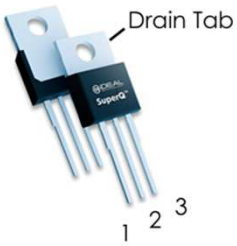
- Motor Control
- Battery disconnect switch
- Switch mode power on primary & secondary

PRODUCT SUMMARY

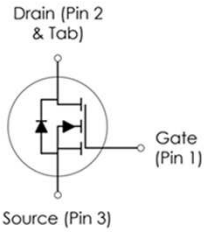
Parameter	Typ	Max	Unit
V_{DS}		200	V
$R_{DS(on)}$ @ 10V	22	25	mΩ
I_D		40	A
Q_G	26.5	34	nC
Q_{SW}	2.7		nC
E_{OSS}	1		µJ

DESCRIPTION

Engineered for high-efficiency motor drives and SMPS, this 200V SuperQ MOSFET delivers ultra-low conduction and switching losses in a robust TO-220 package. Featuring best-in-class $R_{DS(on)}$ and Q_{SW}, it minimizes heat dissipation at both full and partial loads.



TO-220



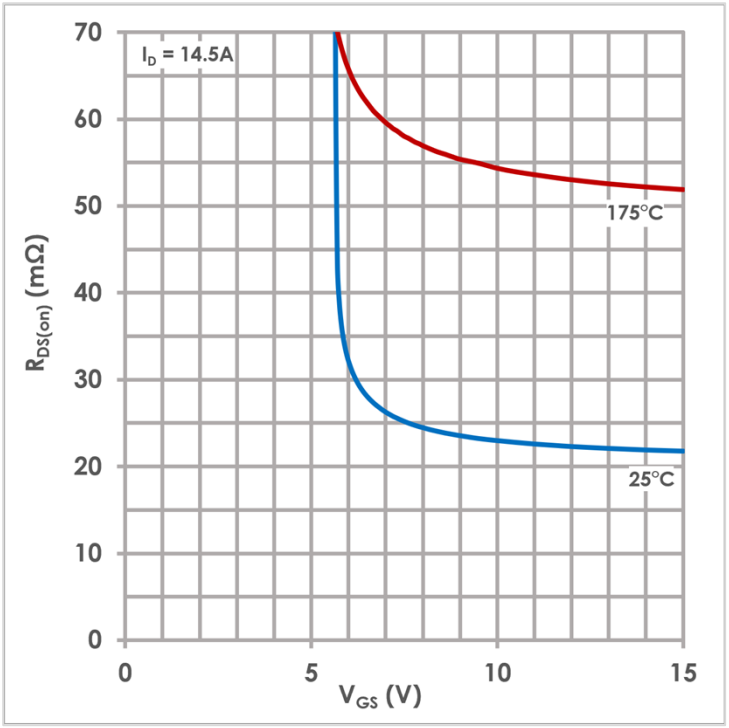


Figure 1: Typical Drain-Source On Resistance

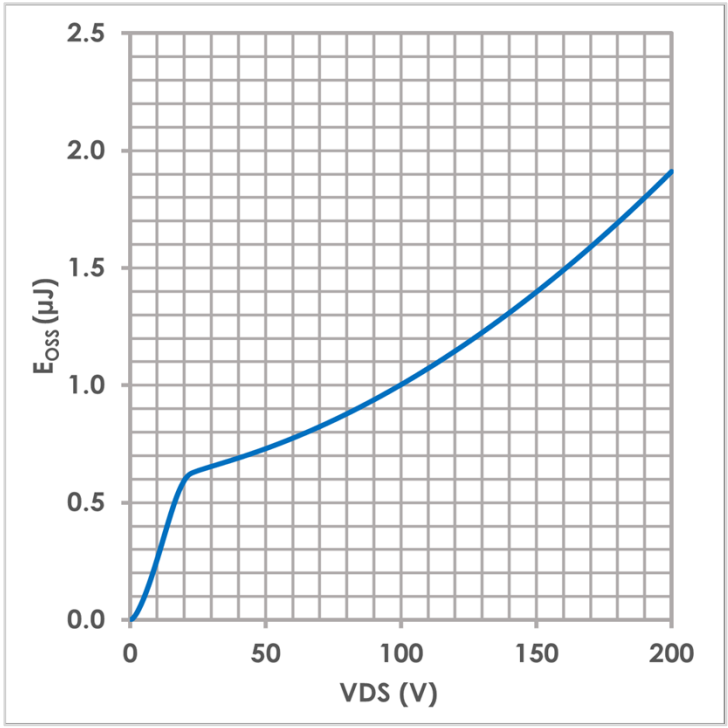


Figure 2: Typical C_{OSS} Stored Energy

ORDERING INFORMATION

Part Number	Package	Marking	Packaging
iS20M028S1PQ	TO-220	iS20M028S1Q	50pc Tube

ABSOLUTE MAXIMUM RATINGS			
SYMBOL	**PARAMETER** (T_A = 25°C unless otherwise specified)	**VALUE**	**UNIT**
V_{GS}	Gate-to-source voltage	± 20	V
I_D	Continuous drain current (silicon limited), TC = 25°C	40	A
	Continuous drain current (silicon limited), TC = 100°C	28	
I_{DM}	Pulsed drain current	154	A
P_D	Power dissipation, TC = 25°C	100	W
T_J, T_{sg}	Operating junction, storage temperature	-55 to 175	°C
E_{AS}	Avalanche energy, single pulse I_D = 48.4A, R_{GS} = 25Ω	159	mJ

THERMAL CHARACTERISTICS					
SYMBOL	**PARAMETER** (T_A = 25°C unless otherwise specified)	**VALUE**			**UNIT**
		MIN	**TYP**	**MAX**	
$R_{\theta JC}$	Junction-to-case thermal resistance – TO-220	-	-	1.5	°C
$R_{\theta JA}$	Junction-to-ambient thermal resistance (1)	-	-	50	°C
$R_{\theta JA}$	Junction-to-ambient thermal resistance, minimal footprint	-	-	62	°C

(1) 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise specified)						
SYMBOL	PARAMETER	TEST CONDITIONS	VALUE			UNIT
			MIN	TYP	MAX	
STATIC CHARACTERISTICS						
BV_{DSS}	Drain-to-source voltage	V_{GS} = 0V, I_D = 1mA	200	-	-	V
I_{DSS}	Drain-to-source leakage current	V_{GS} = 0V, V_{DS} = 160V, T_J = 25°C	-	0.03	1	µA
		V_{GS} = 0V, V_{DS} = 160V, T_J = 125°C(2)	-	13	100	
I_{GSS}	Gate-to-source leakage current	V_{DS} = 0V, V_{GS} = 20V	-	0.4	100	nA
$V_{GS(th)}$	Gate-to-source threshold voltage	V_{DS} = V_{GS}, I_D = 70µA	3.1	3.6	4.1	V
$R_{DS(on)}$	Drain-to-source on-resistance	V_{GS} = 10V, I_D = 14.5A	-	22	25	mΩ
g_{fs}	Transconductance	V_{DS} = 10V, I_D = 14.5A	16	31	-	S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input capacitance (2)	V_{GS} = 0V, V_{DS} = 100V, f = 100kHz	-	1,865	2,425	pF
C_{rss}	Reverse transfer capacitance (2)		-	12	16	
C_{oss}	Output capacitance (2)		-	67	86	
$C_{o(er)}$	Effective output capacitance	V_{DS} = 0 to 100V, V_{GS} = 0V	-	197	-	
R_g	Series gate resistance	f = 1MHz	-	4.5	6.8	Ω
$T_{d(on)}$	Turn-on delay time	V_{DS} = 100V, V_{GS} = 10V, I_{DS} = 14.5A, $R_{G,EXT}$ = 0Ω	-	8.5	-	ns
T_r	Rise time		-	1.9	-	
$T_{d(off)}$	Turn-off delay time		-	24.7	-	
T_f	Fall time		-	11.3	-	
GATE CHARGE CHARACTERISTICS						
Q_g	Gate charge total (2)	V_{DS} = 100V, I_D = 14.5A, V_{GS} = 0 to 10V	-	26.5	34	nC
Q_{sw}	Switching charge (3)		-	2.7	-	
Q_{gd}	Gate to drain charge (2)(3)		-	1.4	1.8	
$Q_{g(th)}$	Gate charge at threshold (3)		-	6.1	-	
Q_{gs2}	Gate to source charge (3)		-	1.3	-	
$V_{plateau}$	Gate plateau voltage		-	5.7	-	V
Q_{oss}	Output charge (2)	V_{DS} = 0 to 100V, V_{GS} = 0V	-	95	108	nC
E_{oss}	Capacitive stored energy		-	1	-	µJ
DIODE CHARACTERISTICS						
V_{SD}	Diode forward voltage	I_{SD} = 14.5A, V_{GS} = 0V	-	1.0	1.2	V
Q_{RR}	Reverse recovery charge	V_{DS} = 100V, I_F = 14.5A, di/dt = 100A/µs	-	425	-	nC
t_{rr}	Reverse recovery time		-	107	-	ns

(2) Defined by design. Not subject to production test

(3) Q_{SW} should be used for switching loss calculations. See Figure 16 for definitions of gate charge. For more information, see Q_{SW} application note on www.idealsemi.com

Ratings and Characteristics Curves (T_A = 25°C unless otherwise specified)

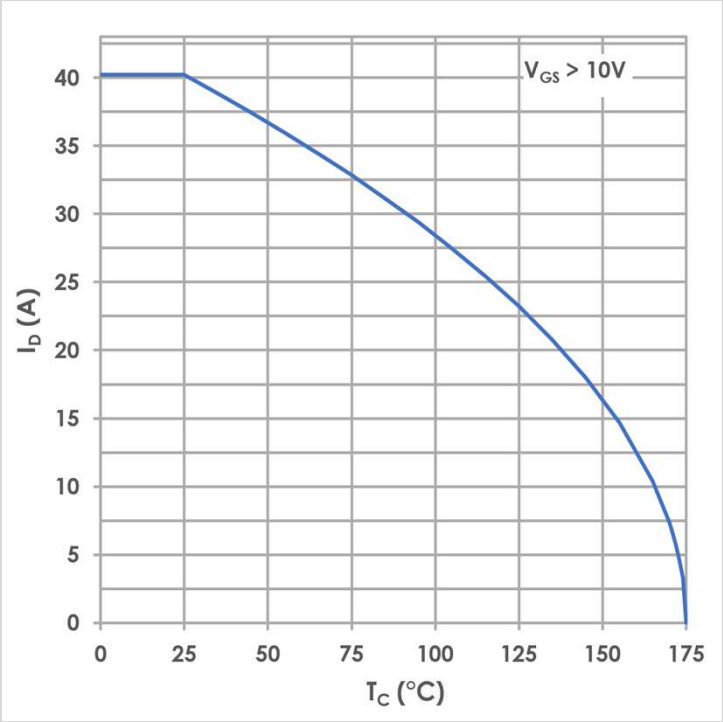


Figure 3: Power Dissipation

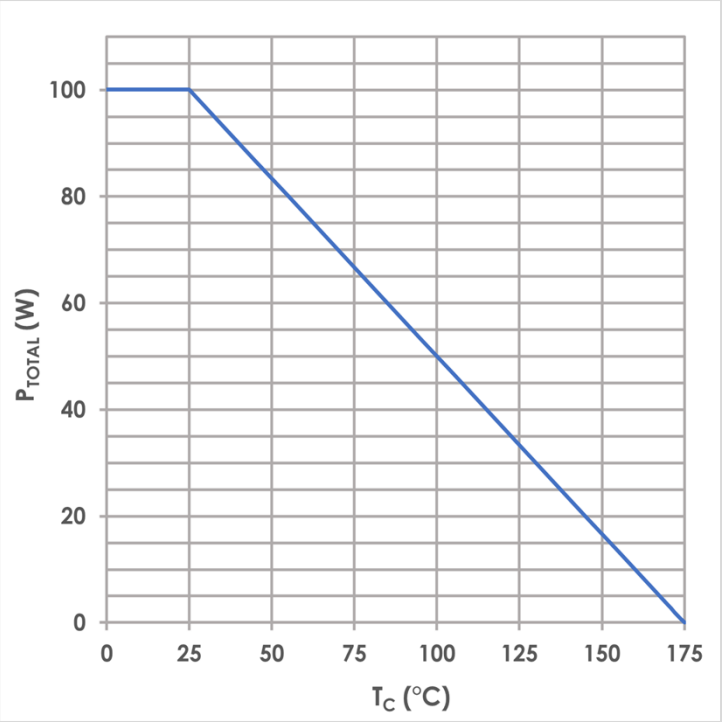


Figure 4: Drain Currents

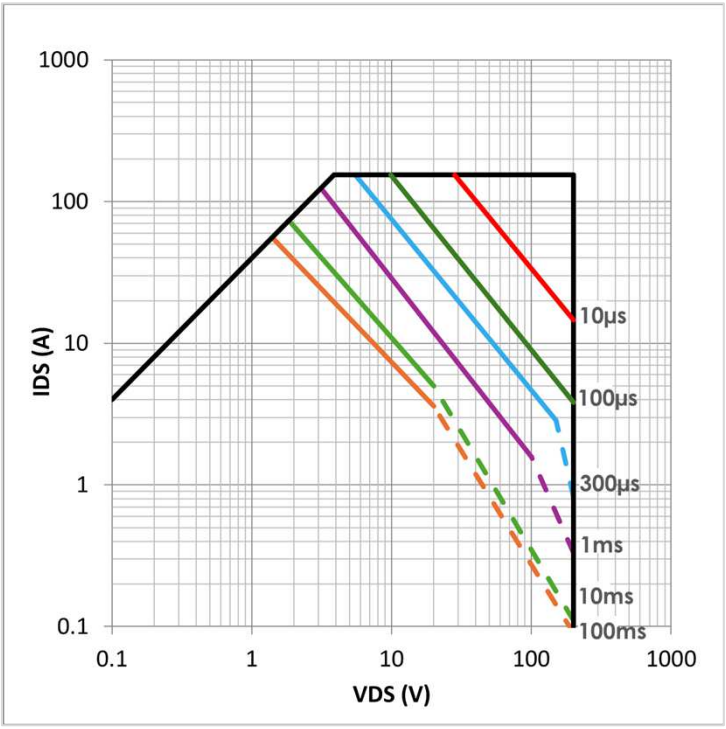


Figure 5: Safe Operating Area

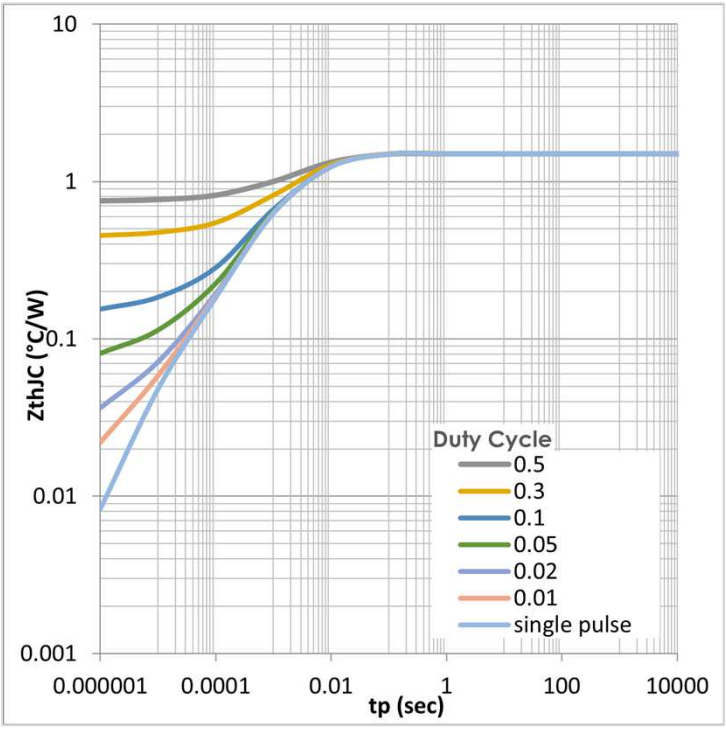


Figure 6: Max Transient Thermal Impedance

Ratings and Characteristics Curves (T_A = 25°C unless otherwise specified)

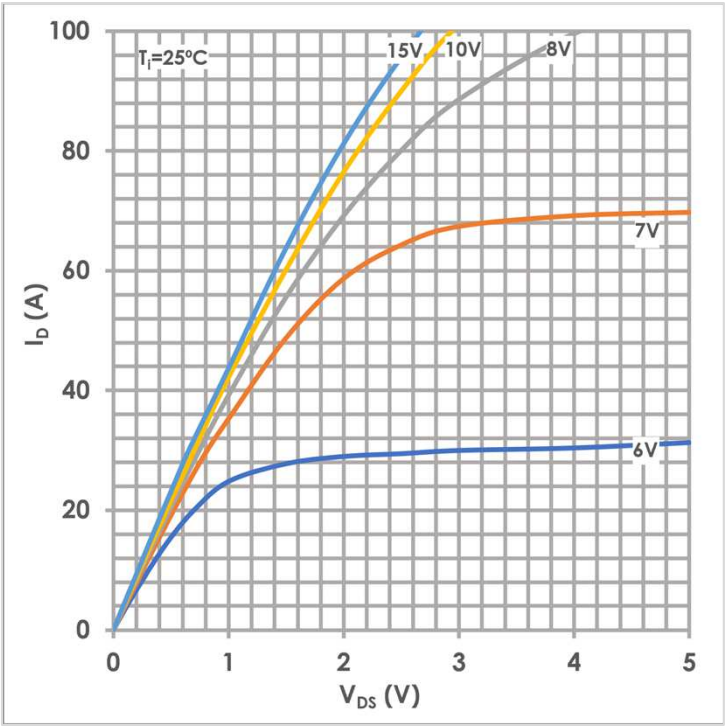


Figure 7: Typical Output Characteristics

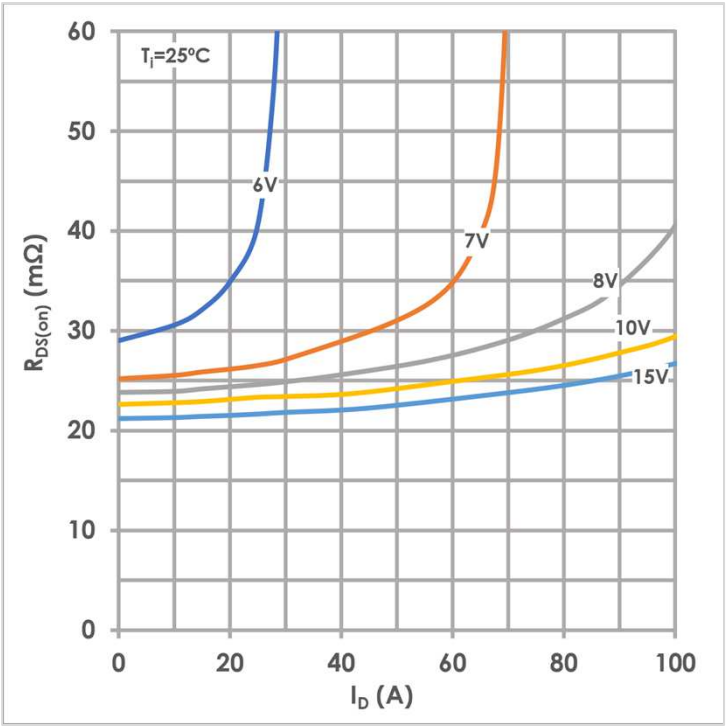


Figure 8: Typical Drain-Source On-Resistance

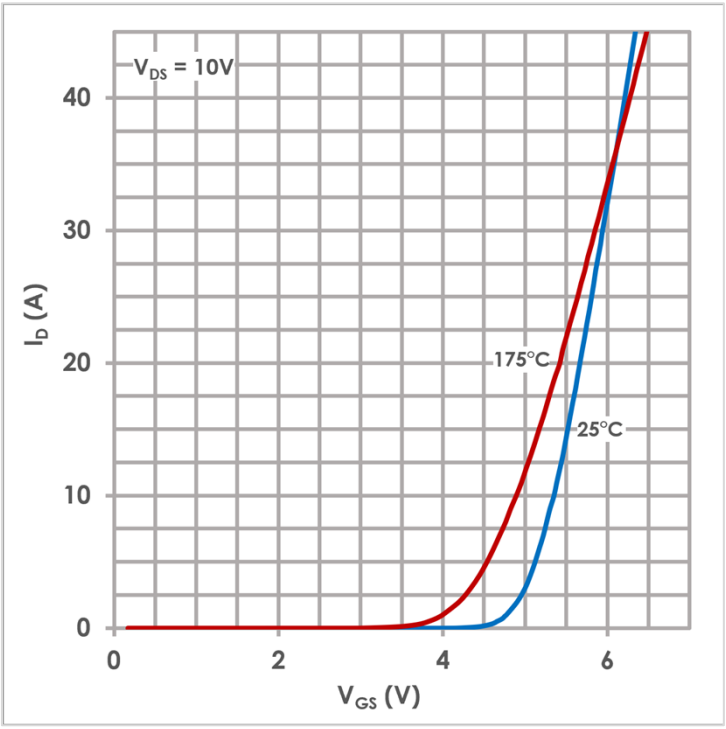


Figure 9: Typical Transfer Characteristics

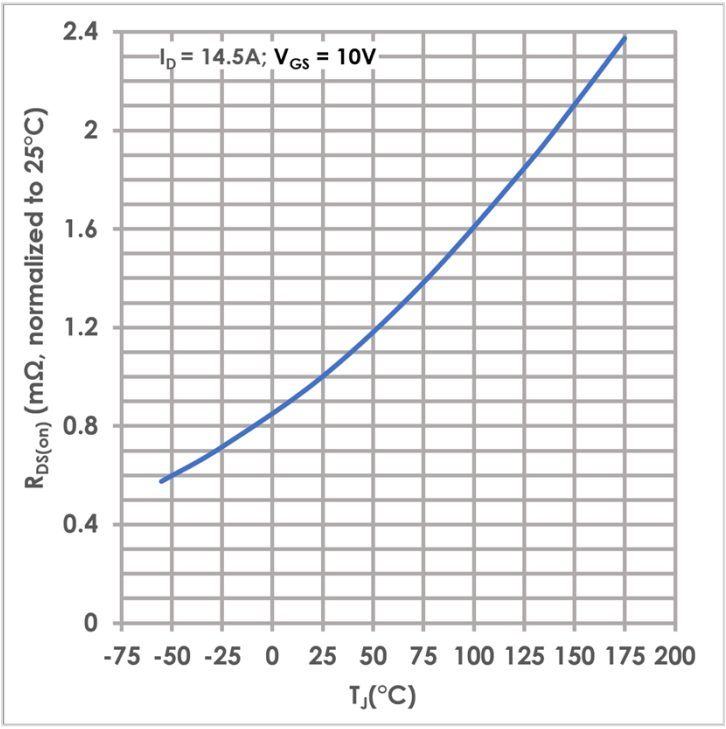


Figure 10: Normalized On-State Resistance vs. Temperature

Ratings and Characteristics Curves (T_A = 25°C unless otherwise specified)

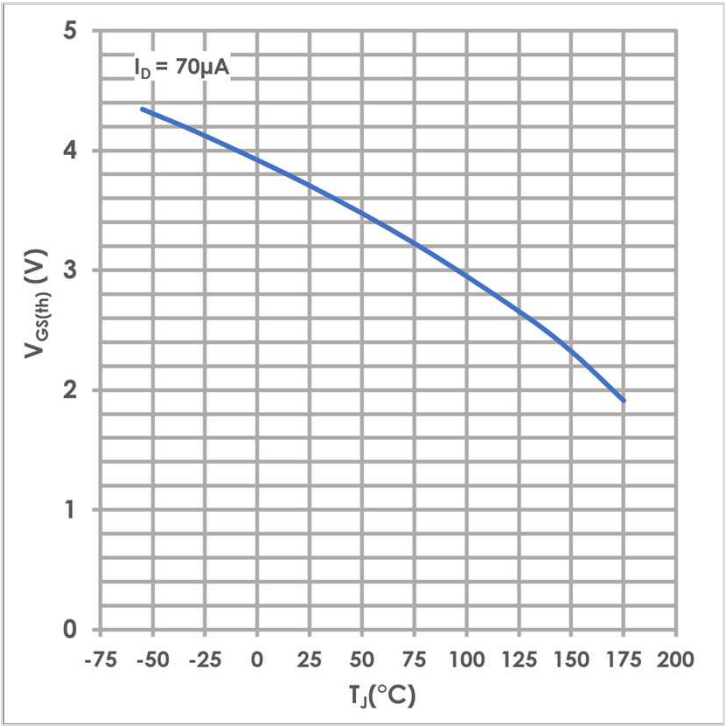


Figure 11: Typical Threshold Voltage

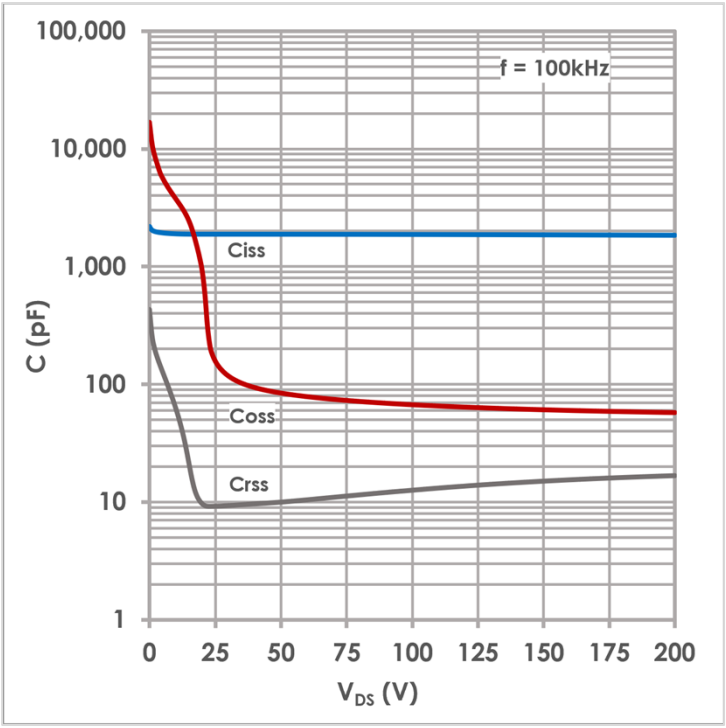


Figure 12: Typical Capacitance

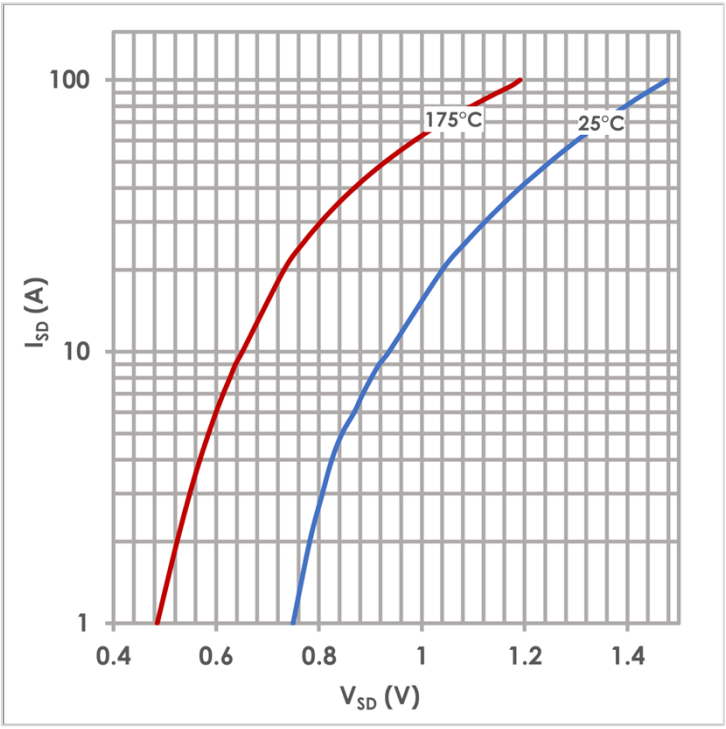


Figure 13: Typical Diode Forward Voltage

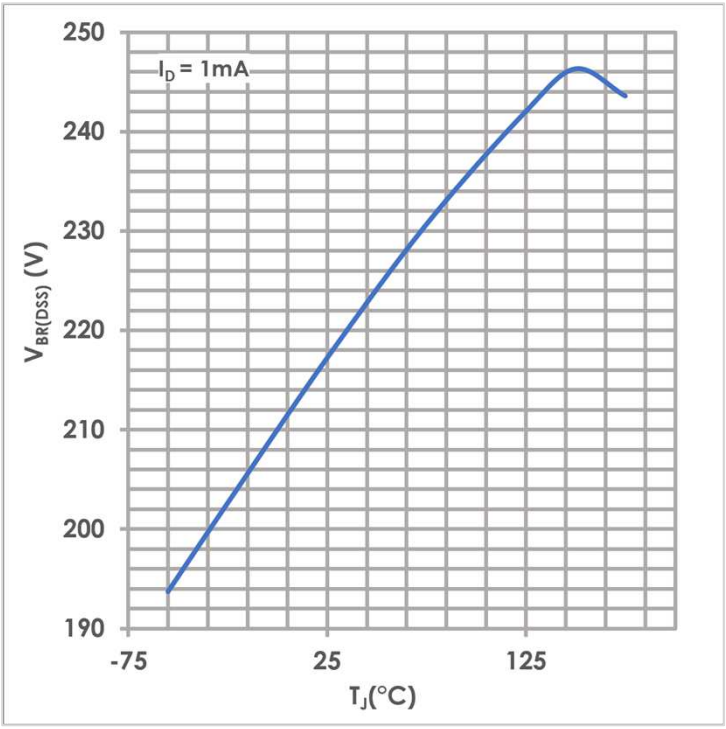


Figure 14: Min Drain-Source Breakdown Voltage

Ratings and Characteristics Curves (T_A = 25°C unless otherwise specified)

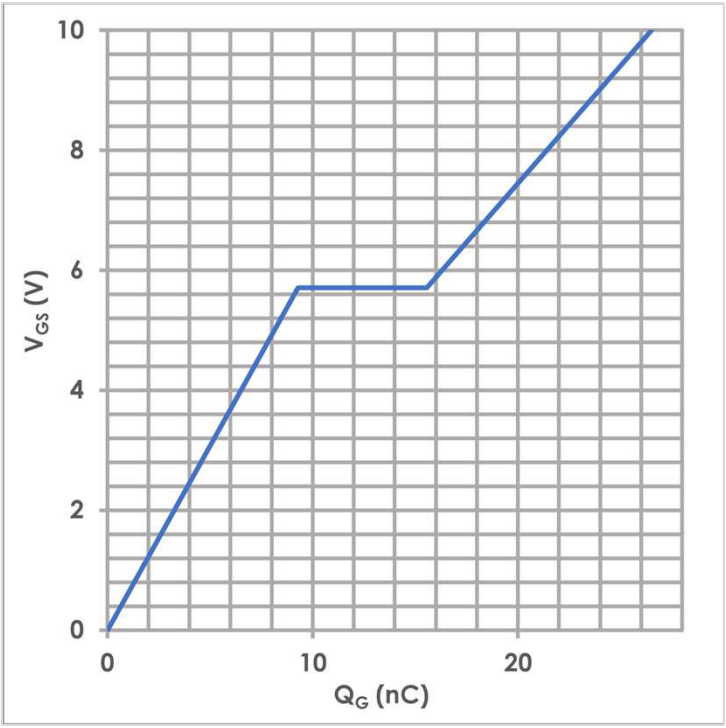


Figure 15: Typical Gate Charge

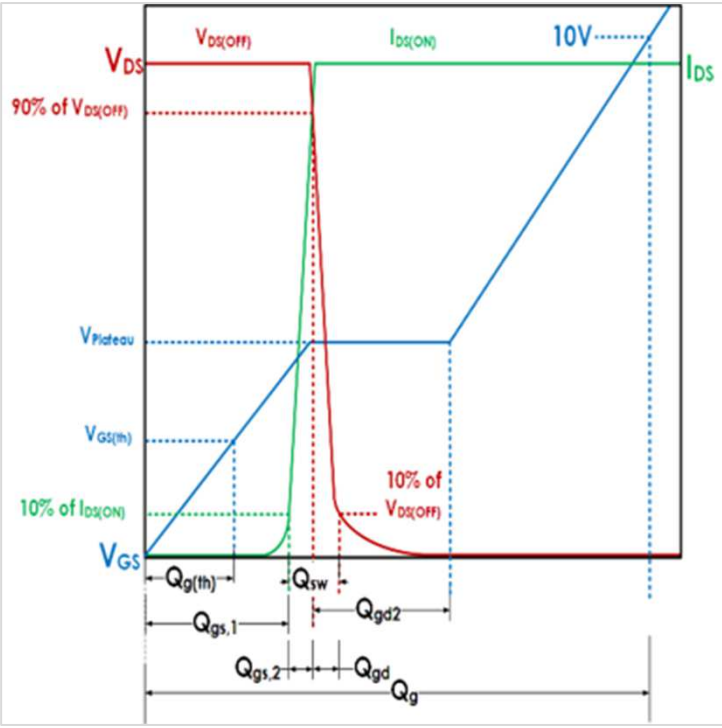
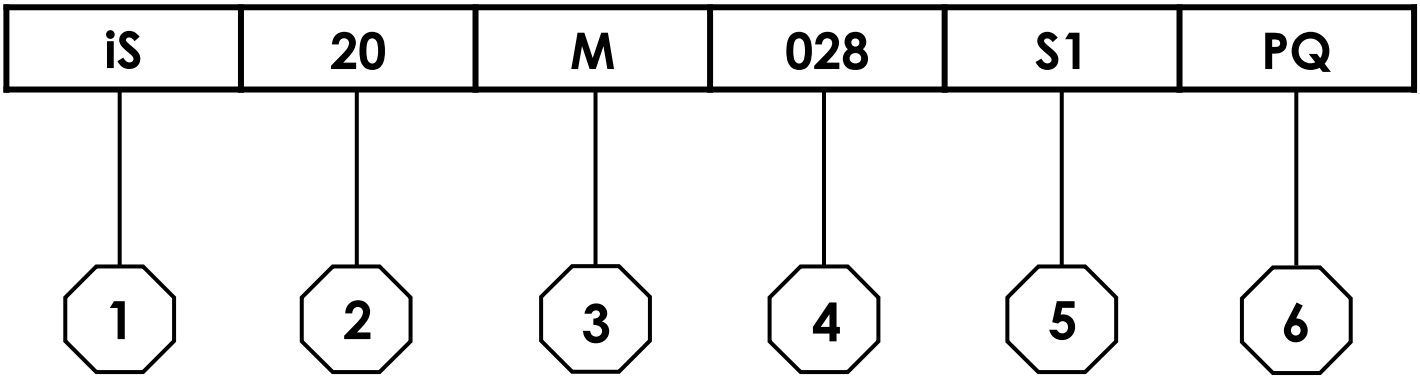


Figure 16: Gate Charge Definitions

DEVICE DECODER RING

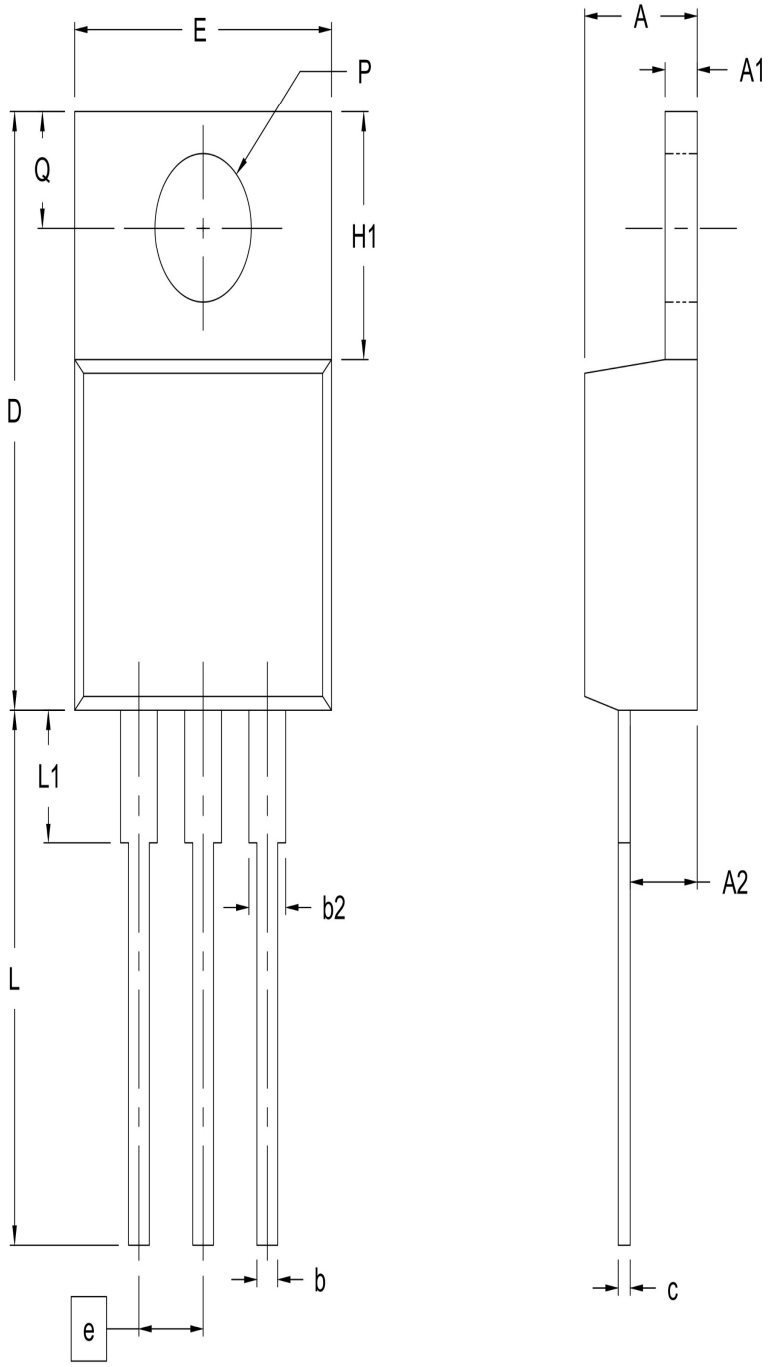
DEVICE CODE:



1	— iDEAL Semiconductor product
2	— Voltage rating divided by 10 (200V)
3	— M = N-Channel MOSFET, Standard Threshold
4	— Drain-to-source resistance
5	— SuperQ® Generation
6	— P = TO-220, Q = AEC-101 Qualified

Package Drawing

TO-220 Package



SYMBOL	MIN	MAX
A	4.19	4.82
A1	1.14	1.40
A2	2.38	2.92
b	0.63	1.01
b2	1.13	1.78
c	0.31	0.64
D	14.22	16.51
E	9.66	10.66
e	2.54 BSC	
H1	5.85	6.85
L	12.70	14.73
L1	2.39	4.42
P	3.54	4.08
Q	2.54	3.42

Notes:
1. All linear dimensions in millimeters
2. Dimensions D and E do not include mold flash or protrusions

Revision History

Revision History		
Version	**Date**	**Comments**
1.0	June 2026	Initial Release

Scan or click QR code for more information and design resources:

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